



Features and Benefits

- Chopper stabilized amplifier stage
- Optimized for BDC motor applications
- New miniature package / thin, high reliability package
- Operation down to 3.5V
- CMOS for optimum stability, quality, and cost
- Ultra low I_{DD} current

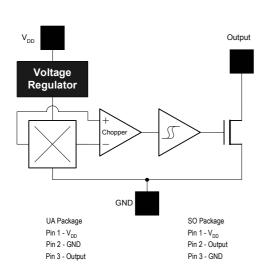
Applications

- Solid state switch
- Brushless DC motor commutation
- Speed sensing
- Linear position sensing
- Angular position sensing
- Current sensing

Ordering Information

Part No. US2881 / US2882 US2881 / US2882 Temperature Suffix E (-40° C to 85° C) L (-40° C to 150° C)

Functional Diagram



Note: Static sensitive device; please observe ESD precautions. Reverse V_{DD} protection is not included. For reverse voltage protection, a 100W resistor in series with V_{DD} is recommended.

Package

SO(SOT-23) or UA (TO-92 flat) SO(SOT-23) or UA (TO-92 flat)

Description

The design specifications and performance of the Melexis US2881 have been optimized for commutation applications in brushless DC motors and automotive speed sensing.

The output transistor will be latched on (B_{OP}) in the presence of a sufficiently strong South pole magnetic field facing the marked side of the package. Similarly, the output will be latched off (B_{RP}) in the presence of a North field. The SOT-23 device is reversed from the UA package. The SOT-23 output transistor will be latched on (B_{OP}) in the presence of a sufficiently strong North pole magnetic field subjected to the marked face.



US2881/2882 CMOS High Sensitivity Latch

US2881 and US2882 Electrical Specifications DC operating parameters: $T_A = 25^{\circ}C$, $V_{DD} = 12V_{DC}$ (unless otherwise specified).

Parameter	Symbol	Test Conditions	Min	Тур	Max	Units
Supply Voltage	V _{DD}	Operating	3.5		24	V
Supply Current	I _{DD}	B <b<sub>OP</b<sub>	1.1	2.0	5.0	mA
Saturation Voltage	V _{DS(on)}	Vdd=12V, I_{OUT} = 20 mA, B>B _{OP}		0.4	0.5	V
Output Leakage	I _{OFF}	$B < B_{RP}$, $V_{OUT} = 24V$		0.01	10.0	μA
Output Rise Time	tr	V_{DD} = 12V, R _L = 1.1K Ω , C _L = 20pf		0.04		μs
Output Fall Time	t _f	V_{DD} = 12V, R _L = 1.1K Ω , C _L = 20pf		0.18		μs

US2881 Magnetic Specifications

Parameter	Symbol	Test Conditions	Min	Тур	Max	Units
Operating Point	B _{OP}	E/L UA, E/L SO, Ta= 25 Vdd=3.5 & 24 volts DC Vdd	0.5	2.0	4.5	mT
Release Point	B _{RP}	E/L UA, E/L SO, Ta= 25 Vdd=3.5 & 24 volts DC Vdd	-4.5	-2.0	-0.5	mT
Hysteresis	B _{hys}	E/L UA, E/L SO, Ta= 25 Vdd=3.5 & 24 volts DC Vdd	1.5	4.0	5.0	mT
Operating Point	B _{OP}	EUA, ESO, Ta= 85 Vdd=3.5 & 24 volts DC Vdd	-1.0	2.0	6.0	mT
Release Point	B _{RP}	EUA, ESO, Ta= 85 Vdd=3.5 & 24 volts DC Vdd	-6.0	-2.0	-1.0	mT
Hysteresis	B _{hys}	EUA, ESO, Ta= 85 Vdd=3.5 & 24 volts DC Vdd	1.5	4.0	5.5	mT
Operating Point	BOP	LUA, LSO, Ta=150°C, Vdd=3.5 & 24 volts DC Vdd	-2.0	2.0	6.0	mT
Release Point	B _{RP}	LUA, LSO, Ta=150°C, Vdd=3.5 & 24 volts DC Vdd	-6.0	-2.0	2.0	mT
Hysteresis	B _{hys}	LUA, LSO, Ta=150°C, Vdd=3.5 & 24 volts DC Vdd	1.5	4.0	5.5	mT

Note: 1 mT = 10 Gauss.



US2882 Magnetic Specifications

Parameter	Symbol	Test Conditions	Min	Тур	Max	Units
Operating Point	BOP	E/L UA, E/L SO, Ta= 25	-2.0	2.0	6.0	mT
		Vdd=3.5 & 24 volts DC Vdd				
Release Point	B _{RP}	E/L UA, E/L SO, Ta= 25	-6.0	-2.0	2.0	mT
		Vdd=3.5 & 24 volts DC Vdd				
Hysteresis	B _{hys}	E/L UA, E/L SO, Ta= 25	1.5	4.0	5.0	mT
		Vdd=3.5 & 24 volts DC Vdd				
Operating Point	BOP	EUA, ESO, Ta= 85	-3.0	2.0	6.0	mT
		Vdd=3.5 & 24 volts DC Vdd				
Release Point	B _{RP}	EUA, ESO, Ta= 85	-6.0	-2.0	3.0	mT
		Vdd=3.5 & 24 volts DC Vdd				
Hysteresis	B _{hys}	EUA, ESO, Ta= 85	1.5	4.0	6.0	mT
		Vdd=3.5 & 24 volts DC Vdd				
Operating Point	BOP	LUA, LSO, Ta=150°C,	-3.5	2.0	6.0	mT
		Vdd=3.5 & 24 volts DC Vdd				
Release Point	B _{RP}	LUA, LSO, Ta=150°C,	-6.0	-2.0	3.5	mT
		Vdd=3.5 & 24 volts DC Vdd				
Hysteresis	B _{hys}	LUA, LSO, Ta=150°C,	1.5	4.0	6.0	mT
		Vdd=3.5 & 24 volts DC Vdd				

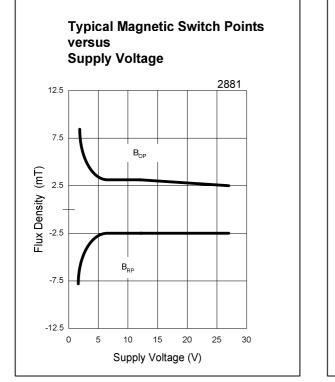
Absolute Maximum Ratings

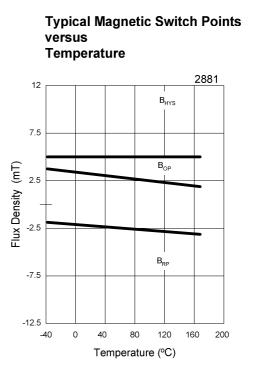
Supply Voltage (Operating), VDD	24V			
Supply Current (Fault), IDD	50mA			
Output Voltage, V _{OUT}	24V			
Output Current (Fault), IOUT	50mA			
Power Dissipation, PD	100mW			
Operating Temperature Range, T _A	-40 to 150°C			
Storage Temperature Range, T_S	-65 to 150°C			
Maximum Junction Temp, T_J	175°C			

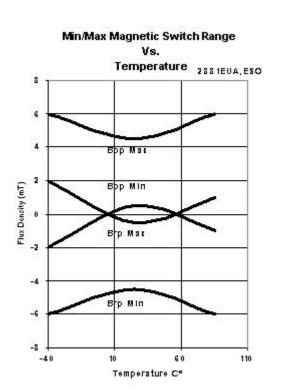


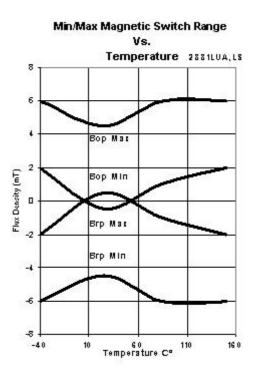
US2881/2882 CMOS High Sensitivity Latch

Performance Graphs

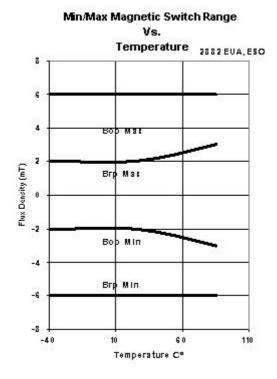


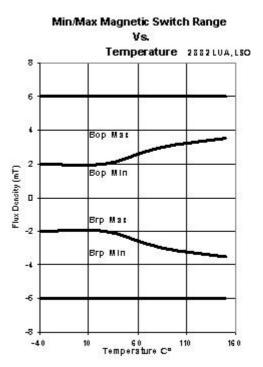


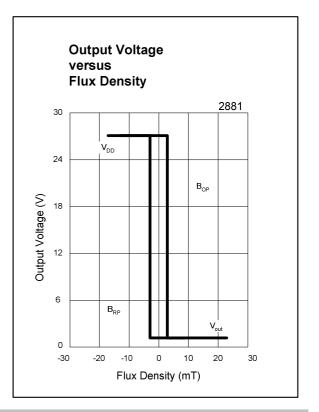








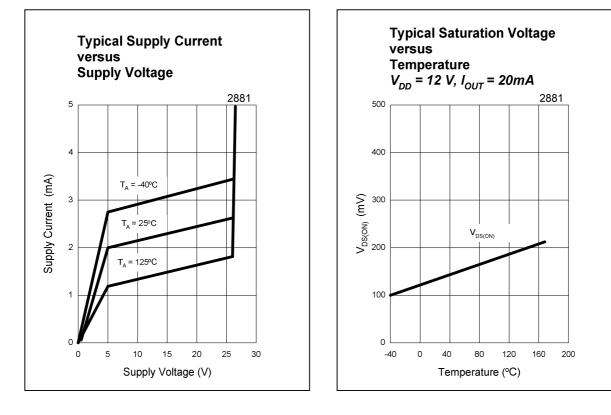


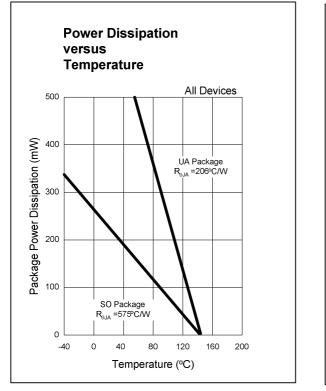


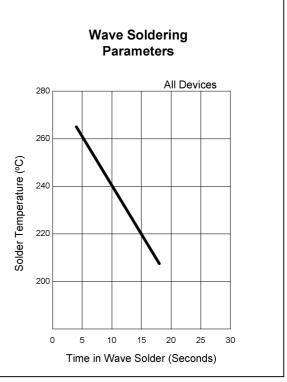


US2881/2882 CMOS High Sensitivity Latch

Performance Graphs









Unique Features CMOS Hall IC Technology

The Chopper Stabilized Amplifier, using switched capacitor techniques, eliminates the amplifier offset voltage, which in bipolar devices is a major source of temperature sensitive drift. CMOS makes this advanced technique possible.

The CMOS chip is also much smaller than the Bipolar chip, allowing very sophisticated circuitry to be placed in less space. The small chip size also contributes to lower physical stress and less power consumption.

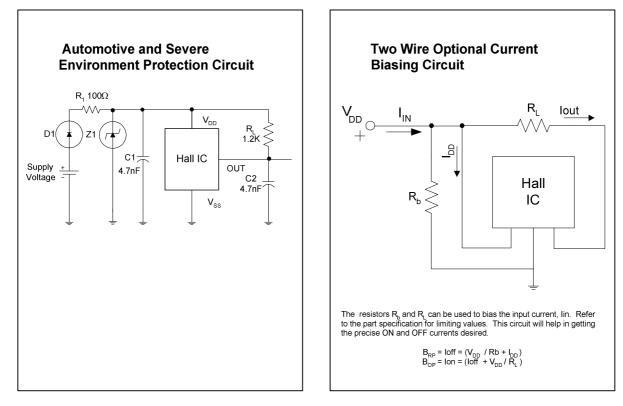
Installation

Consider temperature coefficients of Hall IC and magnetics, as well as air gap and life time variations. Observe temperature limits during wave soldering.

Application Comments

If reverse supply protection is desired, use a resistor in series with the V_{DD} pin. The resistor will limit the Supply Current (Fault), I_{DD} , to 50mA. For severe EMC conditions, use the application circuit below.

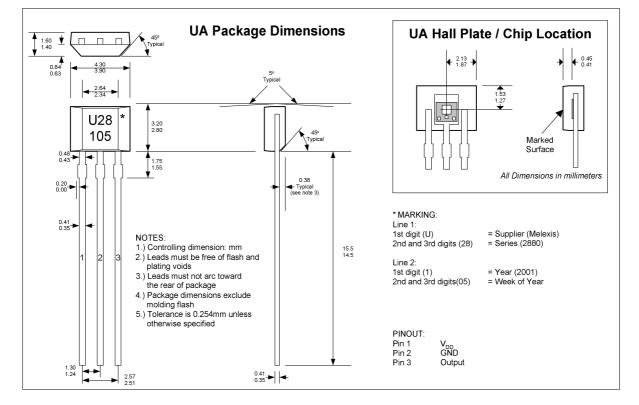
Applications Examples

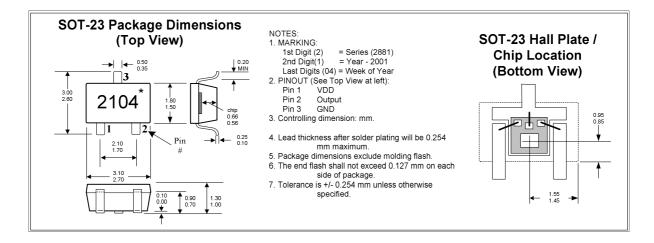






Package Information







Reliability Information

This Melexis device is classified and qualified regarding soldering technology, solderability and moisture sensitivity level, as defined in this specification, according to following test methods:

- IPC/JEDEC J-STD-020 Moisture/Reflow Sensitivity Classification For Nonhermetic Solid State Surface Mount Devices (classification reflow profiles according to table 5-2)
- EIA/JEDEC JESD22-A113 Preconditioning of Nonhermetic Surface Mount Devices Prior to Reliability Testing (reflow profiles according to table 2)
- CECC00802 Standard Method For The Specification of Surface Mounting Components (SMDs) of Assessed Quality
- EIA/JEDEC JESD22-B106 Resistance to soldering temperature for through-hole mounted devices
- EN60749-15 Resistance to soldering temperature for through-hole mounted devices
- MIL 883 Method 2003 / EIA/JEDEC JESD22-B102 Solderability

For all soldering technologies deviating from above mentioned standard conditions (regarding peak temperature, temperature gradient, temperature profile etc) additional classification and qualification tests have to be agreed upon with Melexis.

The application of Wave Soldering for SMD's is allowed only after consulting Melexis regarding assurance of adhesive strength between device and board.

Based on Melexis commitment to environmental responsibility, European legislation (Directive on the Restriction of the Use of Certain Hazardous substances, RoHS) and customer requests, Melexis has installed a Roadmap to qualify their package families for lead free processes also.

Various lead free generic qualifications are running, current results on request.

For more information on manufacturability/solderability see quality page at our website: http://www.melexis.com/html/pdf/MLXleadfree-statement.pdf

ESD Precautions

Electronic semiconductor products are sensitive to Electro Static Discharge (ESD). Always observe Electro Static Discharge control procedures whenever handling semiconductor products.



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Or for additional information contact Melexis Direct:

Europe and Japan: Phone: +32 13 67 04 95 Phone: +1 603 223 2362 E-mail: sales_europe@melexis.com E-mail: sales_usa@melexis.com

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